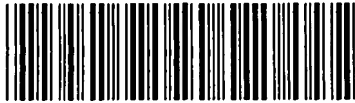


**Search Notes**

Application/Control No.

10/725,432

Examiner

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Applicant(s)/Patent under  
Reexamination

YI ET AL.

Art Unit

2141

**SEARCHED**

Class	Subclass	Date	Examiner
715	734	7/26/2007	DB
709	223	7/26/2007	DB
709	220	7/26/2007	DB
709	219	7/26/2007	DB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	7/26/2007	DB
Double Patenting search	7/26/2007	DB